	o. Item			Specifications	T					
No.			Temperature Compensating Type	High Dielectric Type	Test Method					
1	Operating Temperature Range		5C : -55 to +125°C	R7 : -55 to +125°C R6 : -30 to +85°C						
2	Rated Voltage		See the previous pag	ges	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p.p} or V ^{o.p} , whichever is larger, should be maintained within the rated voltage range.					
3	Appearar	nce	No defects or abnorm	nalities	Visual inspection					
4	Dimensio	ns	Within the specified of	dimensions	Using calipers					
5	Dielectric Strength		No defects or abnorm	nalities	No failure should be observed when 300% of the rated voltage (5C) or 250% of the rated voltage (R7) is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA.					
6	Insulation Resistance		More than 10,000MΩ (Whichever is smalle		The insulation resistance should be measured with a DC voltage not exceeding the rated voltage at 25°C and 75%RH max. and within 2 minutes of charging.					
7	Capacita	nce	Within the specified t	tolerance	The capacitance/Q/D.F. should be measured at 25°C at the					
			30pF min. : Q≧1000		frequency and voltage shown in the table.					
	Q/		30pF max. : Q≥400+20C	Char. 25V min. 16V 10V 6.3V	Char. 5C R7					
8	Dissipation (D.F.)	ssipation Factor F.)		R7, R6 max. max. max. max. max.	Frequency 1±0.1MHz 1±0.1kHz					
	,		C : Nominal Capacitance (pF)							
9	Capacitance Temperature Characteristics	Capacitance Change	Within the specified tolerance (Table A) Within the specified tolerance (Table A)	Char. Temp. Range Reference Temp Cap. Change R7 -55C° to +125C° to +85C° 25°C Within ±15%	The capacitance change should be measured after 5 min. at each specified temperature stage. (1) Temperature Compensating Type The temperature coefficient is determined using the capacitance measured in step 3 as a reference. When cycling the temperature sequentially from step1 through 5, the capacitance should be within the specified tolerance for the temperature coefficient and capacitance change as Table A. The capacitance drift is calculated by dividing the differences between the maximum and minimum measured values in the steps 1, 3 and 5 by the cap. value in step 3.					
7		Capacitance Drift	Within ±0.2% or ±0.05pF (Whichever is larger.)		Step Temperature (°C) 1 25±2 2 -55±3 (for 5C/R7), -30±3 (for F5) 3 25±2 4 125±3 (for 5C/R7), 85±3 (for F5) 5 20±2 (2) High Dielectric Constant Type The ranges of capacitance change compared with the above 25°C value over the temperature ranges shown in the table should be within the specified ranges.					
10	Adhesive Strength of Termination		GNM	rminations or other defect should occur. GNM 2 GNM 2 Solder resist Copper foil	Solder the capacitor to the test jig (glass epoxy board) shown in Fig.1 using a eutectic solder. Then apply 5N force in parallel with the test jig for 10±1 sec. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type a b c d GNM1M2 0.5 1.6 0.32 0.32 GNM212 0.4 1.8 0.15 0.5 GNM212 0.4 1.8 0.15 0.5 GNM214 0.6 2.0 0.25 0.25 GNM214 0.8 2.5 0.4 0.4 (in mm)					
					Continued on the following page.					

	Continued from the preceding page.										
				Specifications							
No.	Ite	em	Temperature Compensating Type	High Dielectri	Туре	Test Method					
		Appearance	No defects or abnorr	nalities			Solder the capacitor to the test jig (glass epoxy board) in the same manner and under the same conditions as (10). The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each 3 mutually perpendicular directions (total of 6 hours).				
		Capacitance	Within the specified	olerance							
11	Vibration Resistance	Q/D.F.	30pF min. : Q≥1000 30pF max. : Q≥400+20C C : Nominal Capacitance (pF)	Char. 25V min. 16V R7, R6 0.025 max. 0.035 max.	10V 0.035 max.	6.3V 0.05 max.					
			No cracking or marki	ng defects should occur		Solder the capacitor on the test jig (glass epoxy board) shown					
			•GNM□□4	•GNM□2	33)	in Fig. 2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3 for 5±1 se. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.				
12	Deflection		1.0		1.0 t=0	.8mm	50 Pressurizing speed: 1.0mm/sec. Pressurize				
			GNM212 2 GNM214 2	a b c .0±0.05 0.5±0.05 0.32±0 .0±0.05 0.6±0.05 0.5±0 .0±0.05 0.7±0.05 0.3±0 .5±0.05 0.8±0.05 0.4±0 Fig. 2	0.05 0.32 .05 0.5±	Capacitance meter 45 Fig. 3					
13	Solderability of Termination		75% of the termination	ons are to be soldered eve	nly and	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120°C for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5°C.					
	Resistanc Soldering		The measured and o	bserved characteristics sh	ould satis						
	Joidening	Appearance	No marking defects				-				
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	R7, R6 : Within ±7.5%			Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the capacitor in a eutectic solder solution at 270±5°C for 10±0.5 seconds. Let sit at room temperature for 24±2 hours (temperature compensating type) or 48±4 hours (high dielectr				
14		Q/D.F.	30pF min. : Q≥1000 30pF max. : Q≥400+20C	Char. 25V min. 16V R7, R6 0.025 0.035	10V 0.035	6.3V 0.05	onstant type), then measure. Initial measurement for high dielectric constant type Perform a heat treatment at 150+0/-10°C for one hour and				
			C : Nominal Capacitance (pF)	max. max.	max.	max.	then let sit for 48±4 hours at room temperature. Perform the initial measurement.				
		I.R.	More than 10,000Mg	or 500Ω • F (Whichever i	s smaller)					
		Dielectric Strength	No failure								

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No.	Ite	em		Specifications					Test Method						
			Temperature Compensating Type High Dielectric Type						rest weared						
	Temperature Cycle			ured and observed characteristics should satisfy the ons in the following table.						Fix the capacitor to the supporting jig in the same manner and					
		Appearance	No marking defects			under the same conditions as (10). Perform the five cycles according to the four heat treatments listed in the following									
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	R7, R6 :	Within ±	7.5%			table. Let sit for 48±4 hours temperature, t	or 24±2 hours s (high dielectri then measure.	(tempera c constar	ture compensant type) at room	iting type)		
15			30pF min. : Q≧1000						Step	1 Min.	2	Max.	4		
15		Q/D.F.	30pF max. : Q≥400+20C		25V min. 0.025	16V 0.035	10V 0.035	6.3V 0.05	Temp. (°C)	Operating Temp. +0/–3	Room Temp.	Operating Temp. +3/–0	Room Temp.		
		Q/D.1 .	C:Nominal	R7, R6	max.	max.	max.	max.	Time (min.)		2 to 3	30±3	2 to 3		
		1.0	Capacitance (pF)	5000	E ()A():	. 1		.\		_		10°C for one h			
		I.R. Dielectric	More than 10,000Ms	2 01 50075	• F (vvnic	cnever	s smallel	()	then let sit for 48±4 hours at room temperature. Perform the initial measurement.						
		Strength	No failure						T OHOTH WIO						
	Humidity State	Steady	The measured and of specifications in the			istics sh	ould sati	sfy the							
16		Appearance	No marking defects												
		Capacitance Change	Within ±5% or ±0.5pF (Whichever is larger)	R7, R6 :	Within ±	:12.5%			Sit the capacitor at 40±2°C and 90 to 95% humidity for 500±7 hours. Remove and let sit for 24±2 hours (temperature compensatin type) or 48±4 hours (high dielectric constant type) at room temperature, then measure.						
		Q/D.F.	30pF and over : Q≥350 10pF and over, 30pF and below: Q≥275+5C/2 10pF and below : Q≥200+10C C : Nominal Capacitance (pF)	Char. R7, R6	25V mir 0.05 max.	n. 16V 0.05 max	5 (V/6.3V 0.05 nax.							
		I.R.	More than 1,000MΩ	or 50Ω • F	(Whiche	ever is s	maller)								
		Dielectric Strength	No failure												
	Humidity	Load	The measured and conspecifications in the	istics sh	ould sati										
		Appearance	No marking defects												
17		Capacitance Change	Within ±7.5% or ±0.75pF (Whichever is larger)	R7, R6 :	Within ±	:12.5%			Apply the rated voltage at 40±2°C and 90 to 95% humidity for 500±12 hours.						
		Q/D.F.	30pF and over : Q≥200 30pF and below : Q≥100+10C/3	Char. R7, R6	25V min 0.05 max.	0.05	5 0	//6.3V 0.05	Remove and let sit for 24±2 hours(temperature compens type) or 48±4 hours (high dielectric constant type) at roor temprature, then muasure. The charge/discharge current is less than 50mA.						
			C : Nominal Capacitance (pF)		ıılax.	max	. <u>n</u>	nax							
		I.R.	More than 500MΩ or	25Ω•F(Whichev	er is sm	aller)		1						
		Dielectric Strength	No failure						-						

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NI-	ltem			Specifications			Test Method			
No.			Temperature Compensating Type	High Die	electric 1	Гуре				
	High Temperature Load		The measured and of specifications in the		tics shou	ıld satisfy the				
		Appearance	No marking defects							
		Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	R7, R6 : Within ±1	2.5%		Apply 200% of the rated voltage for 1000±12 hours at the maximun operating temperature ±3°C. Let sit for 24±2 hours(temperature compensating type) or 48±4 hours(high dielectric constant type) at room temperature, then measure.			
18		Q/D.F.	30pF and over : Q≥350 10pF and over, 30pF and below : Q≥275+5C/2 10pF and below : Q≥200+10C C : Nominal Capacitance (pF)	Char. 25V min. R7, R6 0.04 max.	16V 0.05 max.	10V/6.3V 0.05 max.	The charge/discharge current is less than 50mA. • Initial measurement for high dielectric constant type. Apply 200% of the rated DC voltage for one hour at the maximun operating temperature ±3°C. Remove and let sit for 48±4 hours at room temperature.Perform initial measurement.			
		I.R.	More than 1,000MΩ	or 50Ω • F (Whiche)	er is sm	aller)				

Table A

		Capacitance Change from 25℃ (%)							
Char.	Nominal Values (ppm/℃) Note 1	-5	5℃	-3	0℃	−10 °C			
	(ppin/c) Note i	Max.	Min.	Max.	Min.	Max.	Min.		
5C	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11		

Note 1 : Nominal values denote the temperature coefficient within a range of 25 to 125°C.